



Gallium Nitride Power MMICs – Fact and Fiction

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Introduction

- Gallium Nitride has many attractive characteristics
 - High operating voltage capability (V_{BD})
 - High current capability (I_{MAX})
 - Good microwave performance (G_{MAX} , f_T , f_{MAX})
 - Good low noise performance (NF_{MIN})
 - High thermal conductivity Silicon Carbide substrate
- Should be ideal for microwave power applications!



Introduction

- Use of GaN based technology is rapidly growing
 - Military (Radar, EW, Communications)
 - Infrastructure (Basestation, Weather Radar, Satcom)
 - Commercial (CATV, Test equipment)
- Numerous circuit functions have been demonstrated
 - Power amplifiers
 - Low noise amplifiers
 - RF control components



Introduction

- GaN MMIC design however is not without issues
- Some are obvious
 - High voltage / high current
 - Thermal
- Some are less so
 - Wideband power amplifier designs
 - Power combining
 - User interface / driver circuitry



High Output Impedance = More Bandwidth?

- High voltage operation = higher output impedance
 - Reduced transformation ratios
 - Lower loss, wider band matching networks
 - Less complex combining networks or more power
- All true! Sometimes
- Narrow to moderate bandwidth designs do benefit
- Low frequency wideband designs also benefit



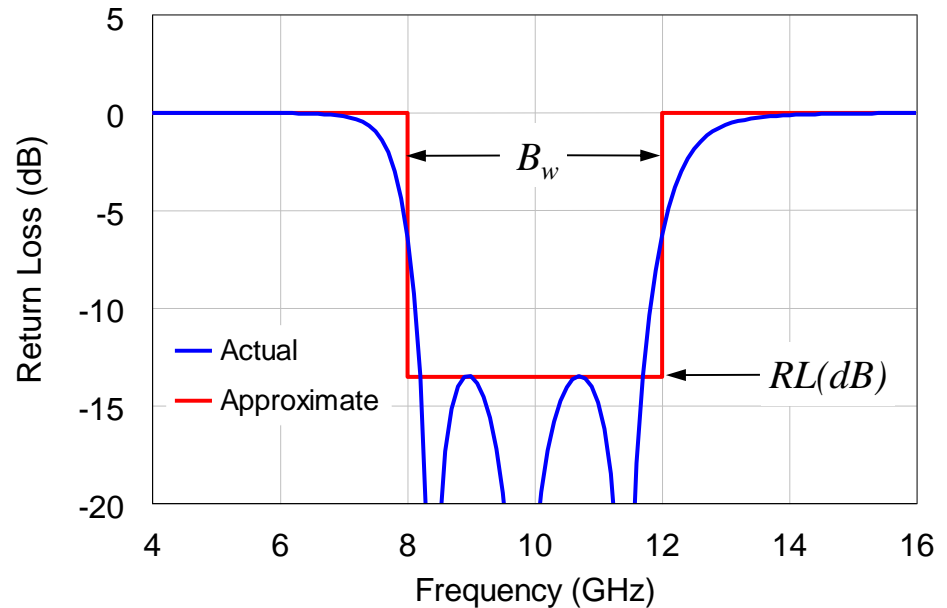
High Output Impedance = More Bandwidth?

- This not always true for reactively matched wideband microwave frequency designs
- A restriction comes into play: Bode-Fano Limit [1]

$$\int_0^{\infty} \ln|1/\Gamma(\omega)|d\omega \leq \frac{\pi}{R_p C_p}$$

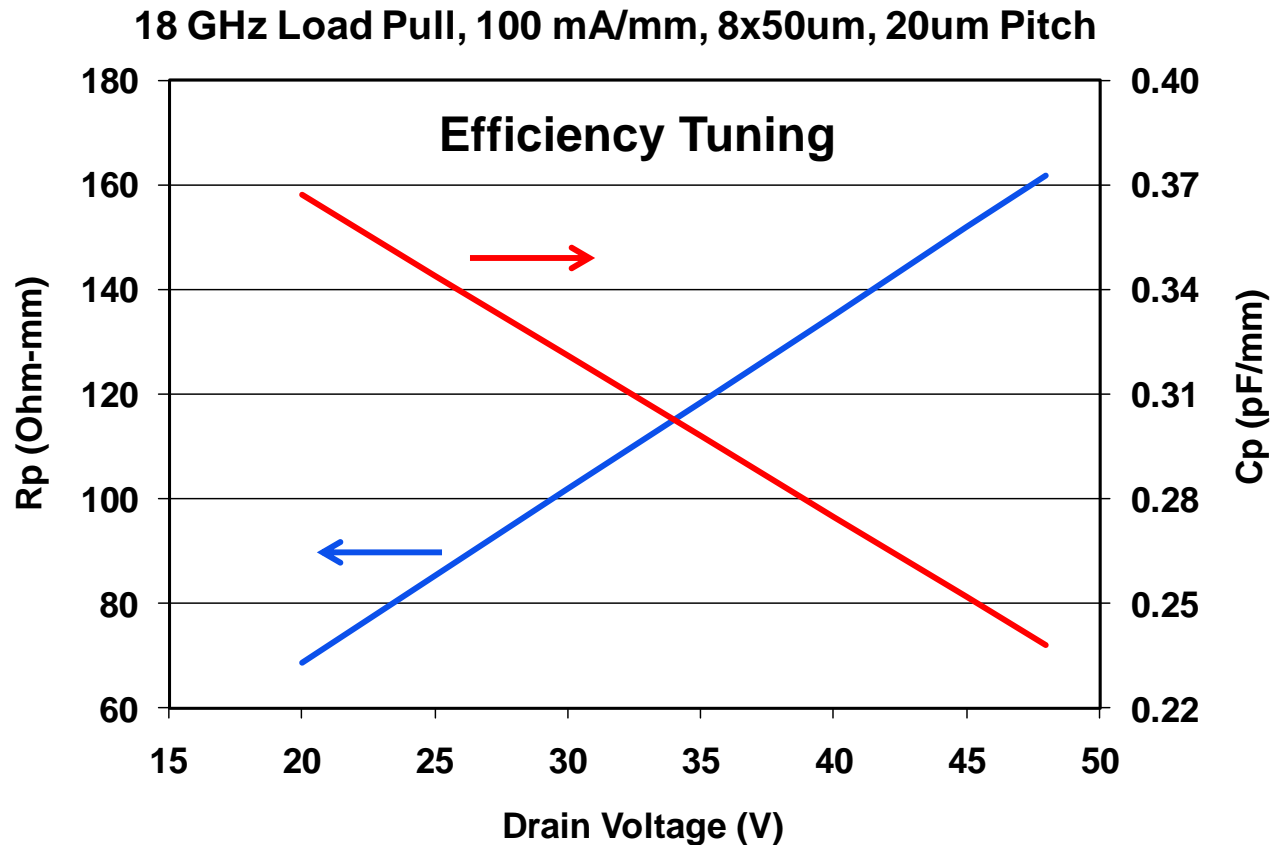
$$B_w < \frac{4.343}{R_p C_p RL(dB)}$$

$$R_p \approx \beta \frac{V_D - V_K}{I_{\max}}$$



High Output Impedance = More Bandwidth?

- $R_p C_p$ Bias Dependence for a 0.25 μm GaN FET



High Output Impedance = More Bandwidth?

- So why does this matter ?
- Bandwidth limit for a 6V GaAs PHEMT is $> 30\text{GHz}$
- The efficiency tuned load target for a $0.25\mu\text{m}$ GaN HEMT at 18GHz and $V_D = 35\text{V}$ is....

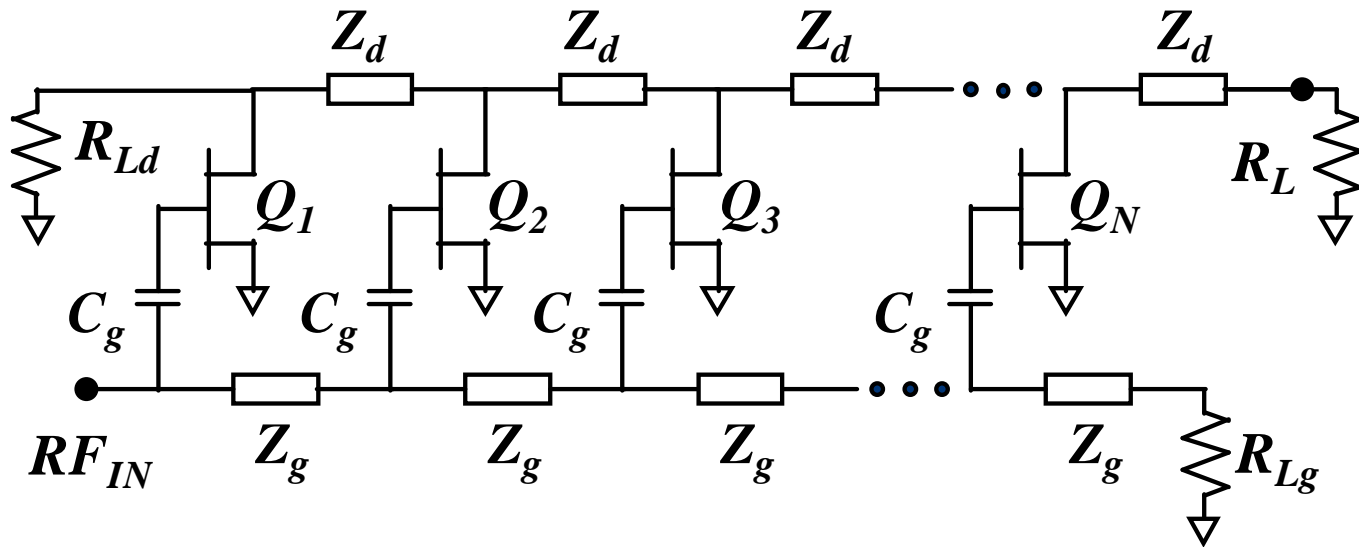
$$R_p = 120 \Omega\text{-mm} \quad C_p = 0.3 \text{ pF/mm}$$

- For 20dB return loss bandwidth is $< 6\text{GHz}$!
- This assumes an infinite order matching network!!



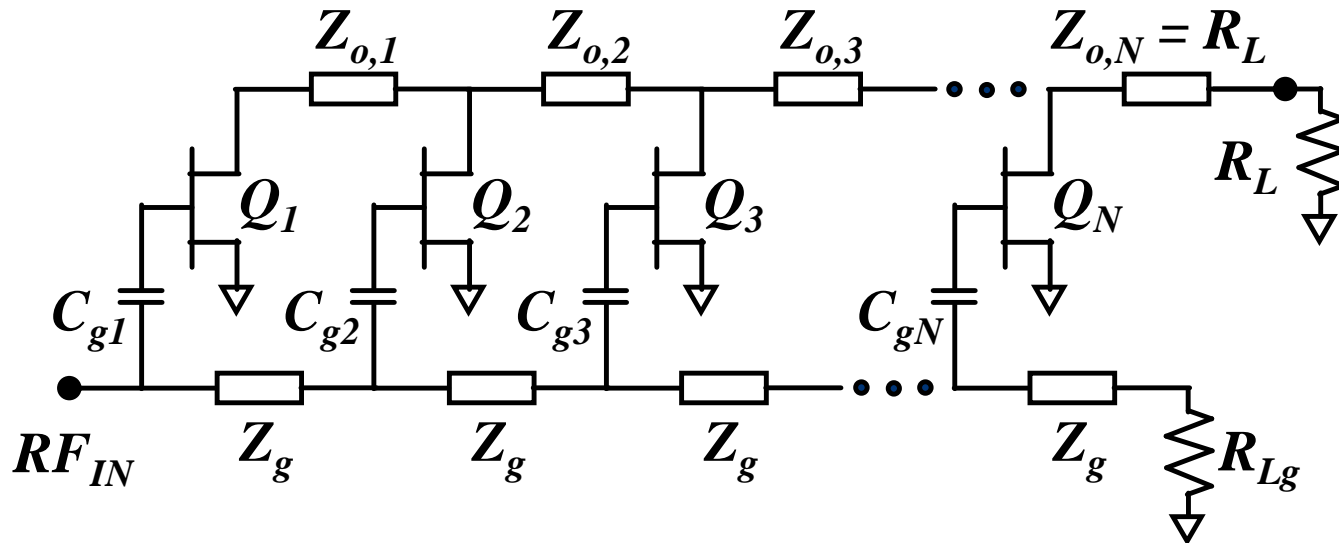
Dealing with Bode-Fano

- Bandwidth increases if C_P is reduced
- Fundamental idea behind the distributed amplifier
- Uniform distributed amplifier – **Not a good PA**



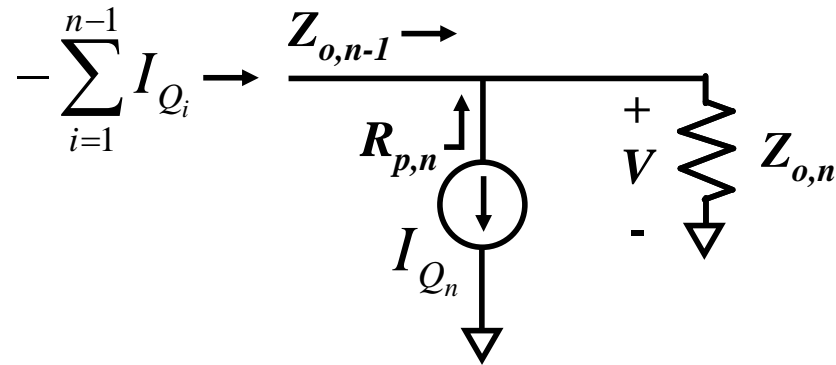
Dealing with Bode-Fano

- Power performance is improved with a non-uniform distributed power amplifier topology (NDPA) [2]
 - Output termination R_{Ld} removed
 - Output line $Z_{o,n}$ and gate capacitors $C_{g,n}$ are varied



Dealing with Bode-Fano

- So how are the drain line impedances varied?
- Simplified low frequency nth FET output model



- Summing the currents at the drain node

$$\sum_{i=1}^{n-1} I_{Q_i} + I_{Q_n} + \frac{V}{Z_{o,n}} = 0$$



Dealing with Bode-Fano

- Solve for $R_{p,n}$ and assume uniform drive and loading such that the current scales with periphery

$$R_{p,n} = \frac{V}{-I_{Q_n}} = Z_{0,n} \left(1 + \frac{1}{I_{Q_n}} \sum_{i=1}^{n-1} I_{Q_i} \right) = \frac{Z_{0,n}}{W_{Q_n}} \sum_{i=1}^n W_{Q_i}$$

- Normalize $R_p = R_{p,n} W_{Q_n}$ and solve for $Z_{0,n}$

$$Z_{0,n} = \frac{R_p (\Omega \cdot mm)}{\sum_{i=1}^n W_{Q_i}}$$



Dealing with Bode-Fano

- The drain line impedance for the N th FET will be,

$$Z_{0,N} = R_L = \frac{R_p (\Omega \cdot mm)}{\sum_{i=1}^N W_{Q_i}} \quad \text{or} \quad \frac{R_p (\Omega \cdot mm)}{R_L (\Omega)} = \sum_{j=1}^N W_{Q_j}$$

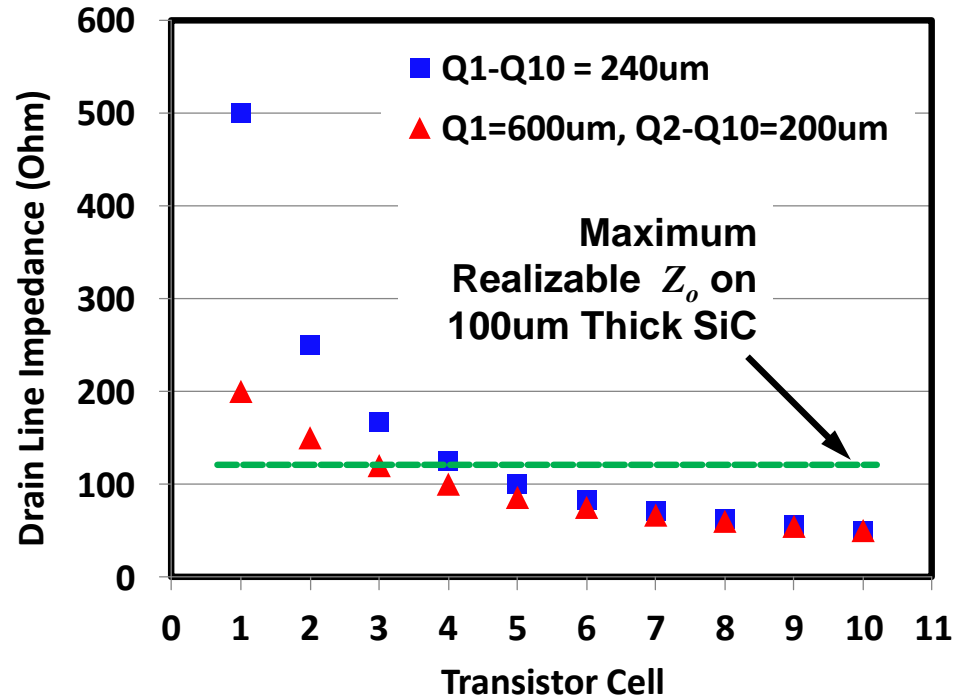
- This condition fixes the total periphery and therefore the expected output power capability of the amplifier
- Increase periphery (power) by increasing R_p (V_D) or decreasing the amplifier load impedance R_L



Dealing with Bode-Fano

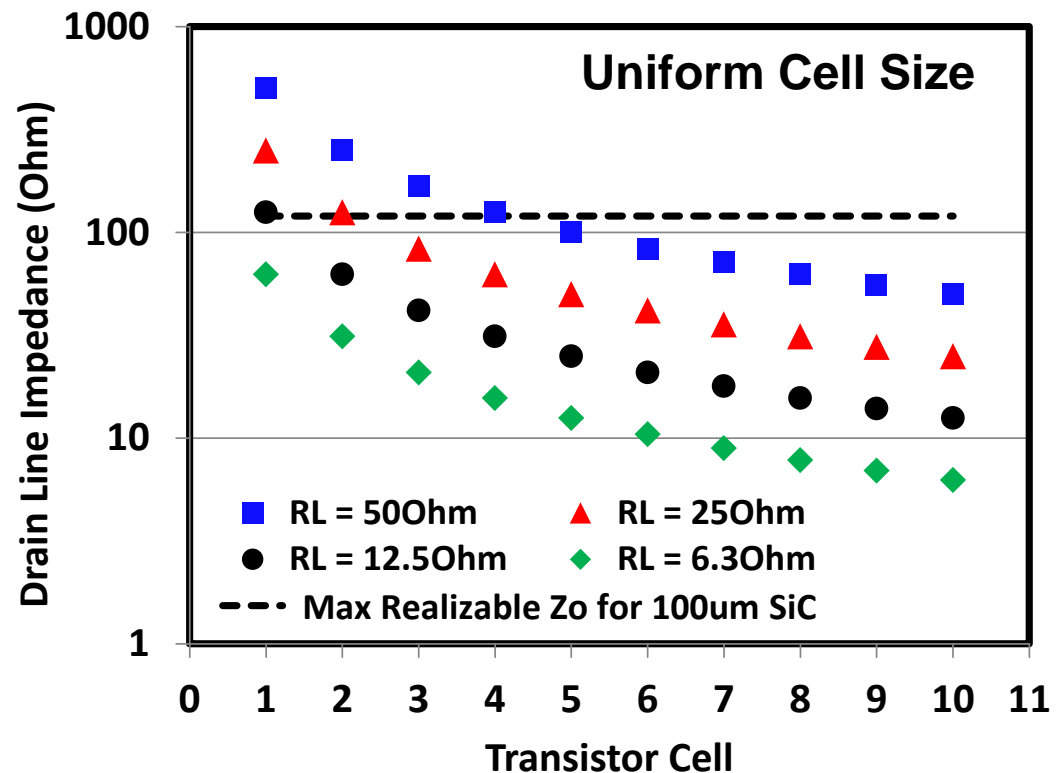
- Consider the following example for $R_L = 50\Omega$

- $N = 10$ FET cells
- $R_p = 120 \Omega\text{-mm}$
- Total Periphery: 2.4mm
- Power: 7-12W (3-5W/mm)
- Very high Z_o
- Q_1 size sets max Z_o [3]
- **The first transistors are poorly loaded!**



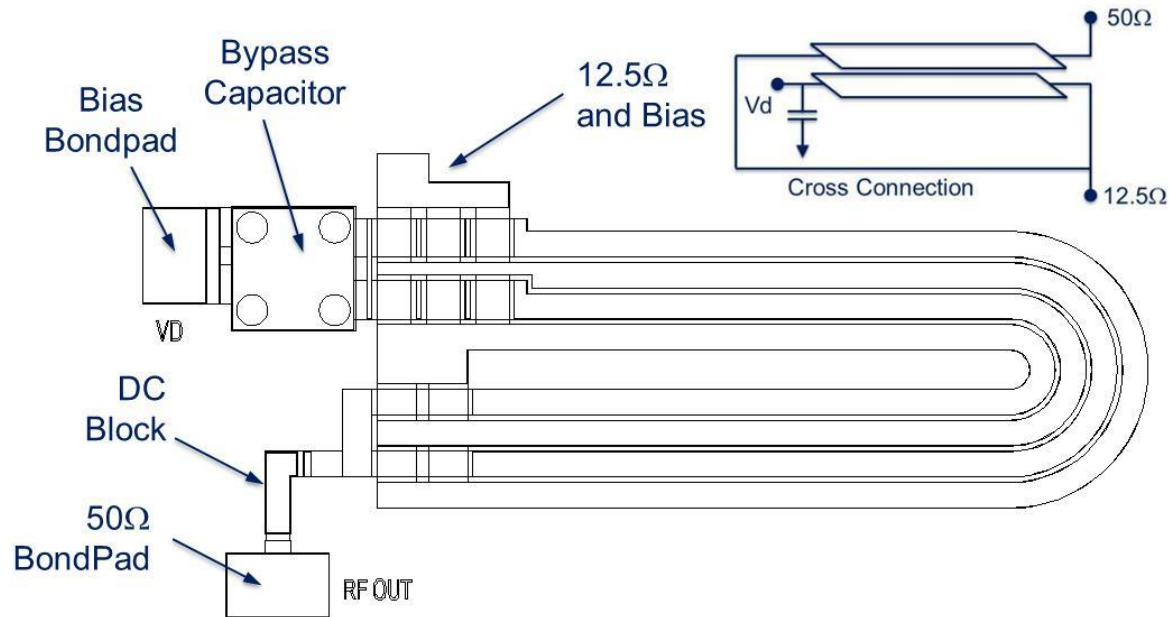
Dealing with Bode-Fano

- Reduce load impedance – Requires transformer
- Trade bandwidth for output power and realizability
- Power @ 3W/mm
 - $R_L=50\Omega \Rightarrow 7W$
 - $R_L=25\Omega \Rightarrow 14W$
 - $R_L=12.5\Omega \Rightarrow 28W$



Dealing with Bode-Fano

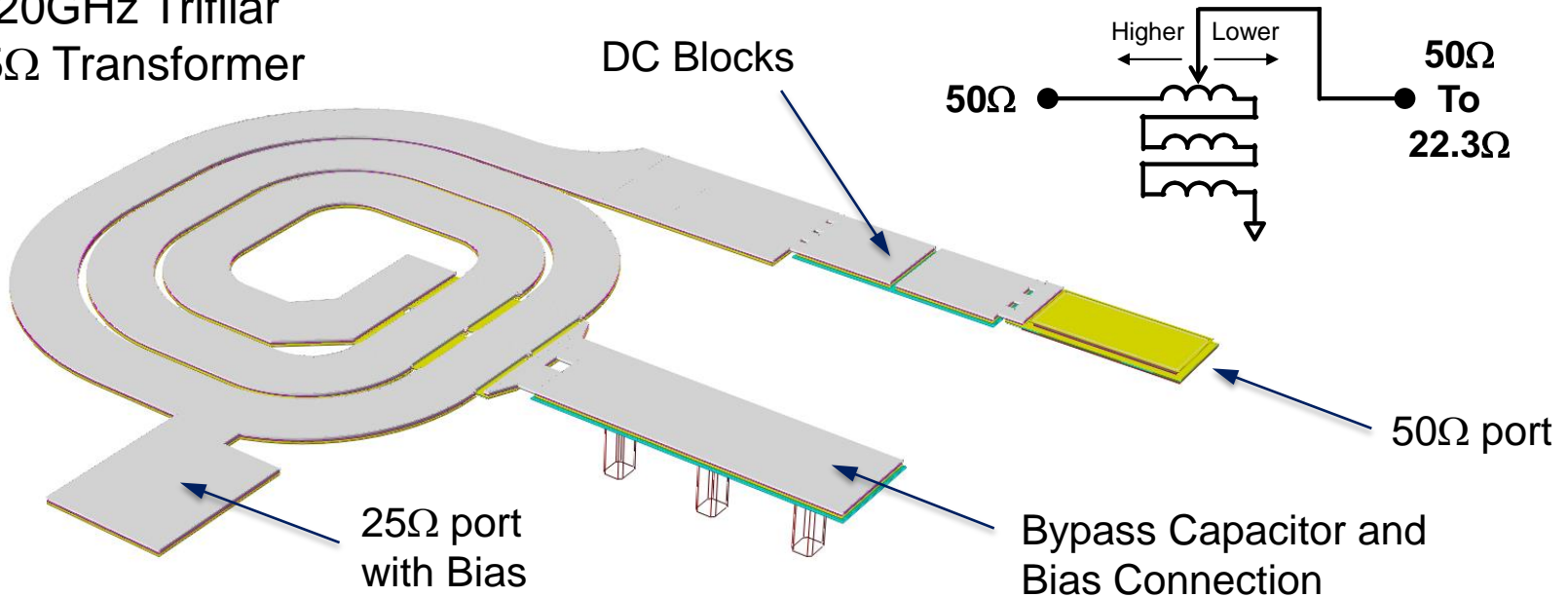
- For a 4:1 impedance transformation ($R_L=12.5\Omega$) a useful circuit is Ruthroff connected coupled lines [4]
- GaN on 100 μm thick SiC realizations are capable of about 4:1 bandwidth [5]



Dealing with Bode-Fano

- Bandwidth can be traded for transformation ratio
- Trifilar transformer - up to 2.25:1 transformation
- Trifilar coupled lines on GaN ~ 10:1 bandwidth [6,7]

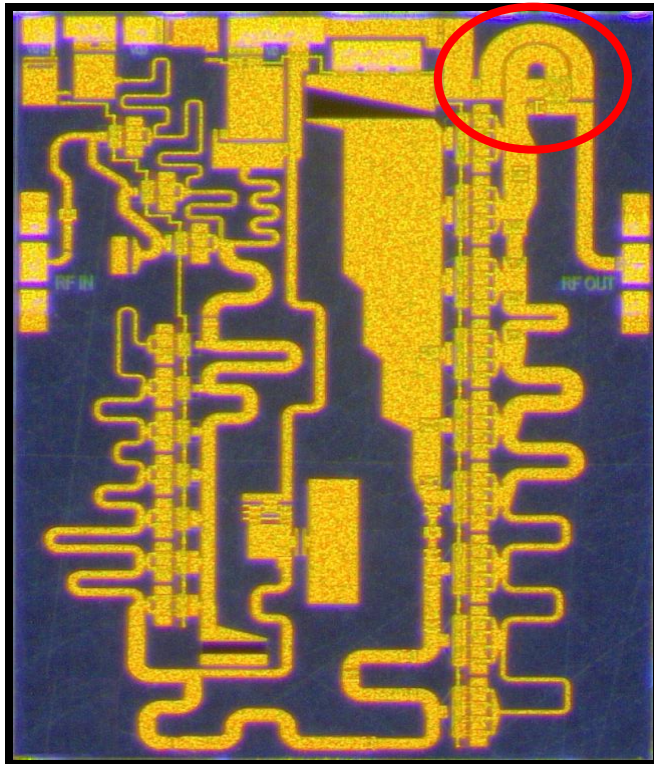
2-20GHz Trifilar
25Ω Transformer



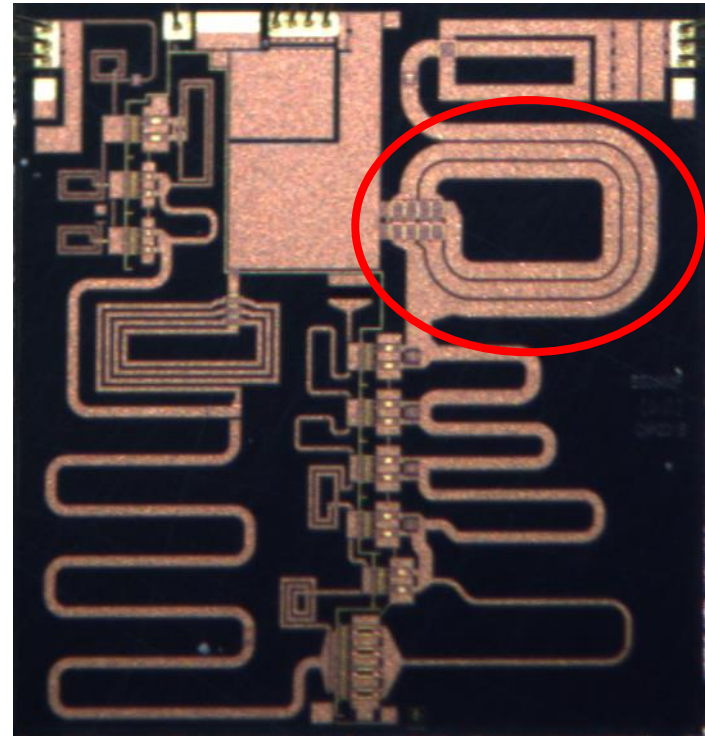
Dealing with Bode-Fano

- Transformer based NDPA MMIC examples

18-40GHz NDPA with a Ruthroff connected output transformer



1-8GHz NDPA with a Trifilar connected output transformer



Why is My Part So Hot?

- Most GaN MMIC processes use SiC as a substrate
- Thermal conductivity of SiC exceeds that of copper
- Heat is transferred effectively to the back of the die
- The power density of GaN HEMTs 3-5X higher than a GaAs PHEMT of equal periphery
- The power added efficiency is however similar
- The problem: 3-5X more heat flux to be removed



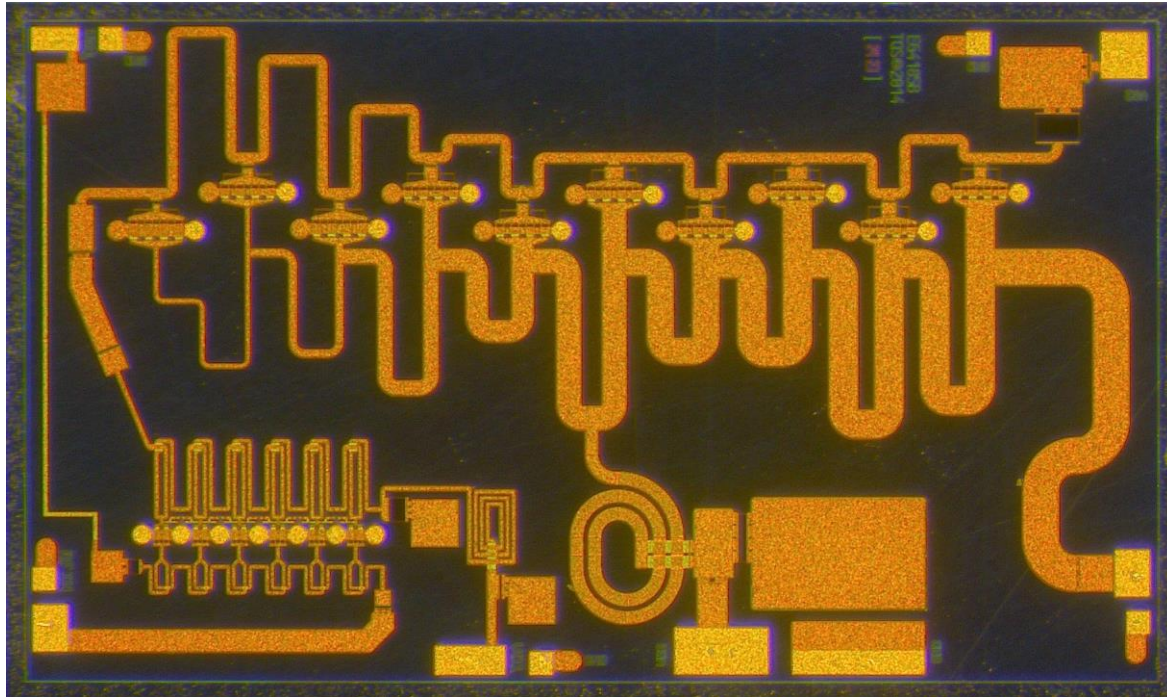
Why is My Part So Hot?

- Thermal management burden is placed on the user
- Failure to remove heat \Rightarrow Higher MMIC base temp
- Today designers must practice thermal management
 - Increase gate pitch \Rightarrow Reduced RF performance
 - Increase cell separation \Rightarrow Die size and stability
 - Individual source vias (ISVs) \Rightarrow Die size
 - Tune for Max PAE \Rightarrow Reduced Power or linearity



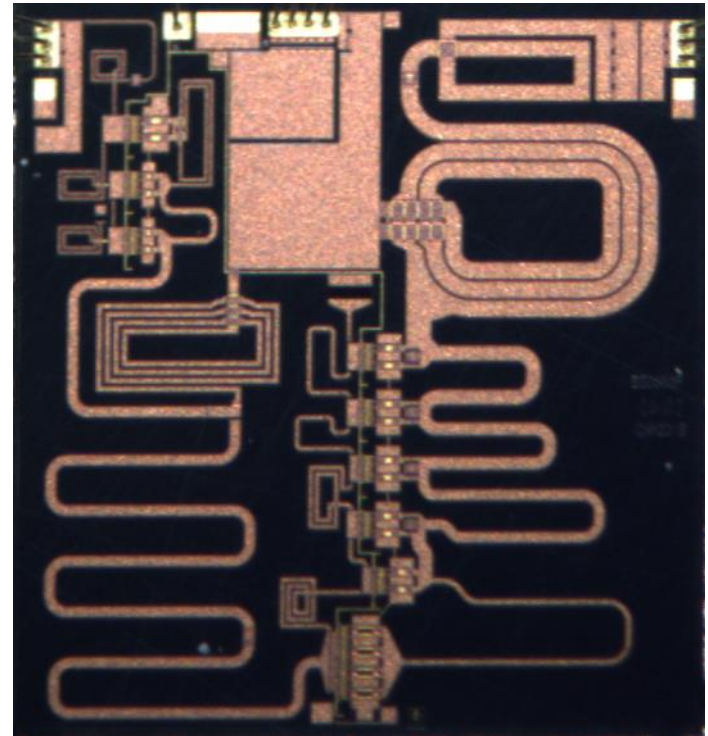
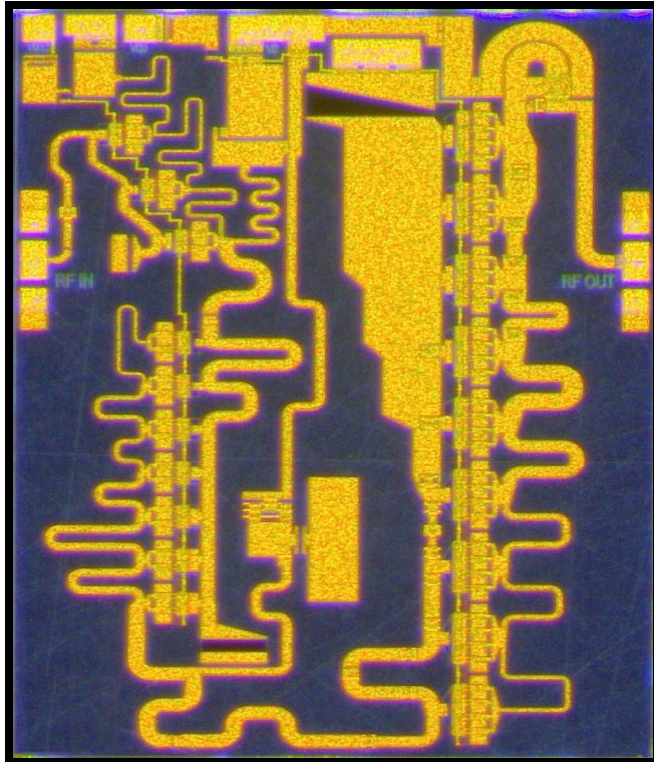
Why is My Part So Hot?

- An example of staggering the FET cells



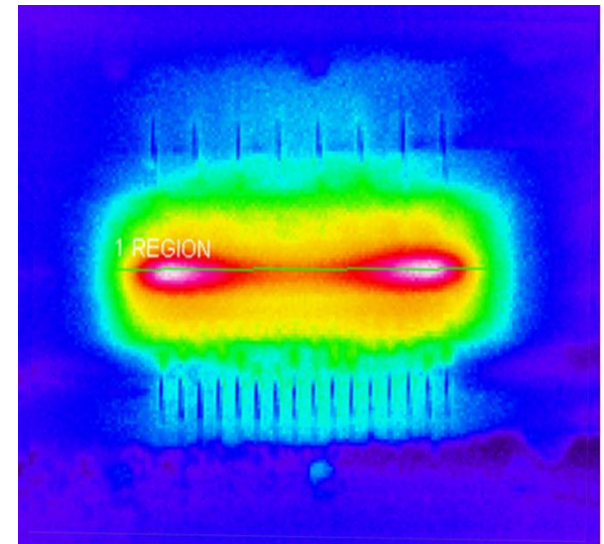
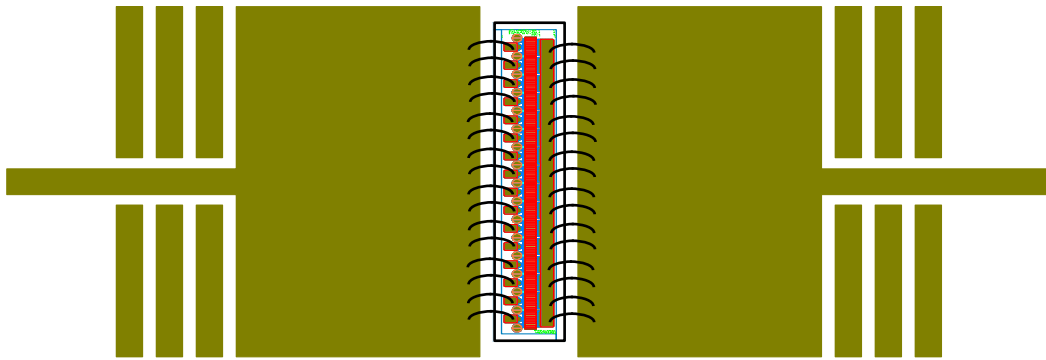
Why is My Part So Hot?

- Staggering the FET cells
- Using ISV FET cells



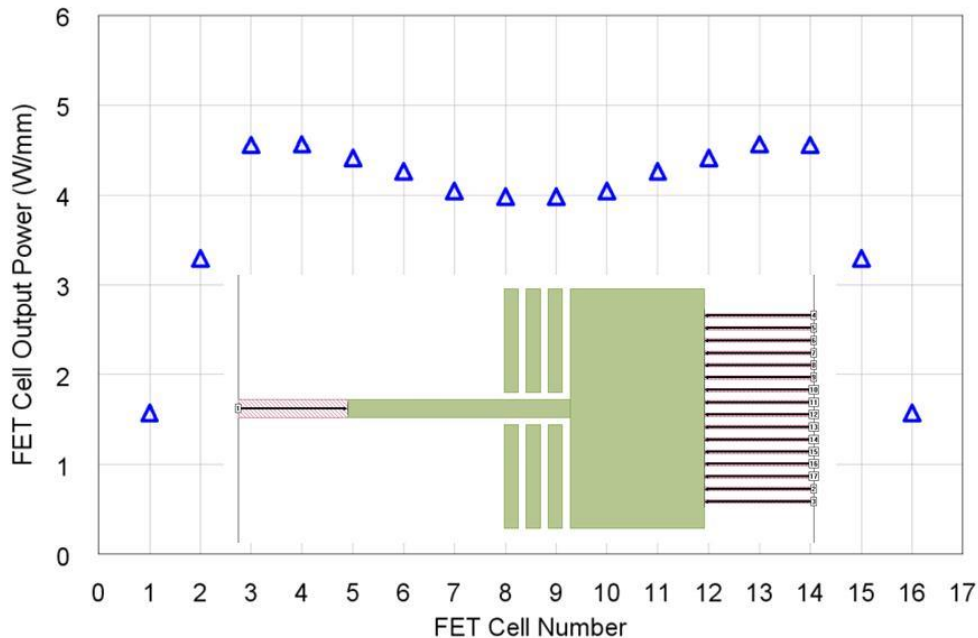
Why is My Part So Hot?

- An interesting example - power was reported power to be 1dB low for the 20mm FET die with loadpull prematch
- An unexpected temperature distribution was noted



Why is My Part So Hot?

- A detailed simulation revealed non-uniform drive and loading across the prematch connection ports
- Integrating over the 16 unit FET cells and normalizing to the maximum



$$10 \log \left(\frac{\sum_{j=1}^{16} P_j}{16 \times 4.5} \right) = -0.9 \text{ dB}$$



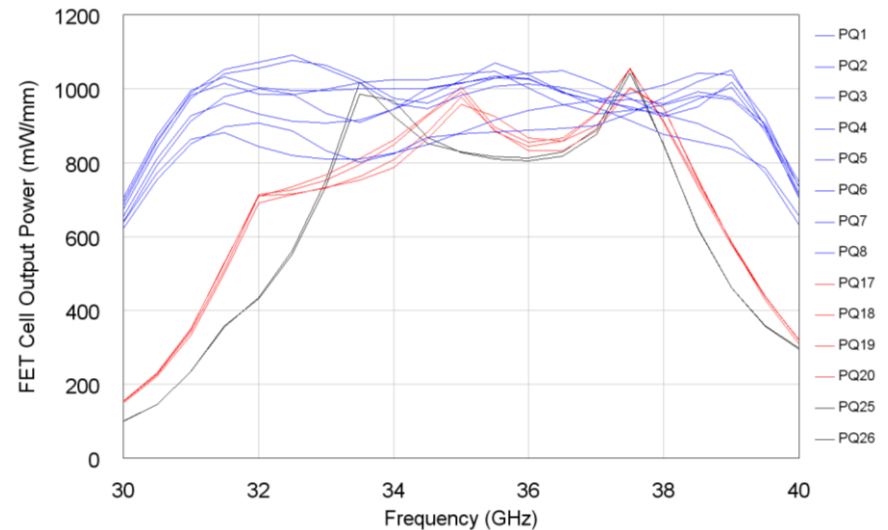
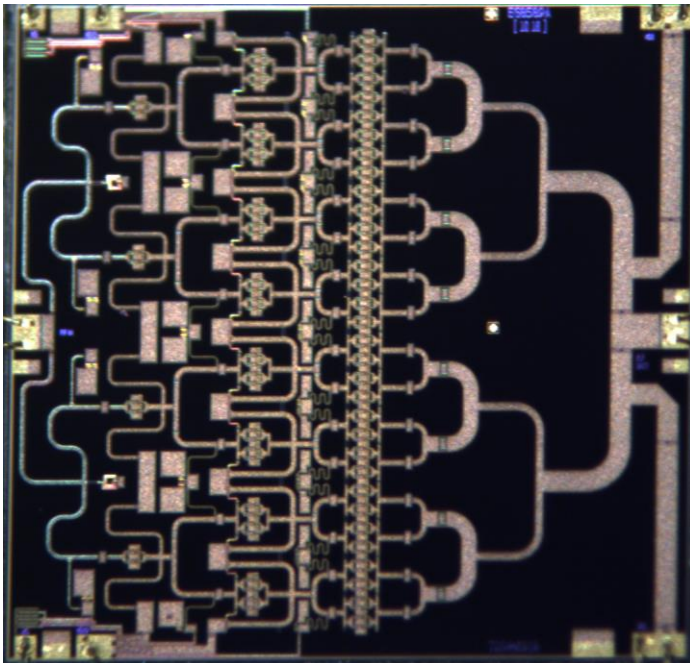
The Devil is in the Power Combining

- The odd temperature distribution for the 20mm FET is caused by asymmetries in the combining network
- Some sources of combiner asymmetry
 - Mutual inductance between parallel bond wires
 - Mode formation due to curves and bends
 - Coupling between microstrip lines
 - Sharing source vias between adjacent cells
 - Nonuniform temp. from adjacent cell heating



The Devil is in the Power Combining

- 3-stage 16-way combined GaAs Ka-band PA MMIC



Half-Fold Symmetry Assumed

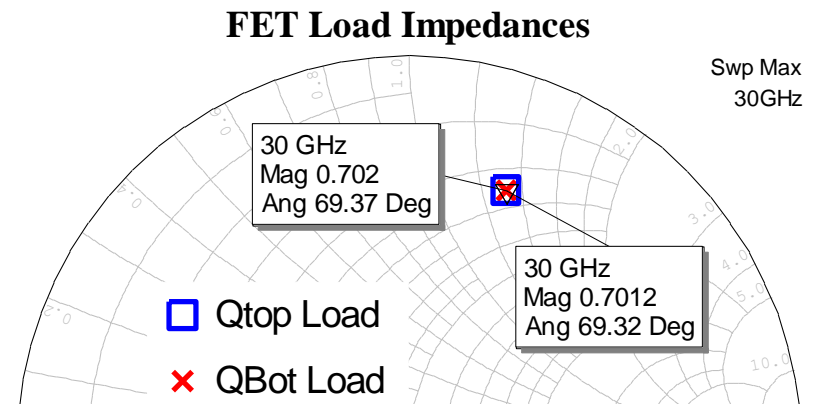
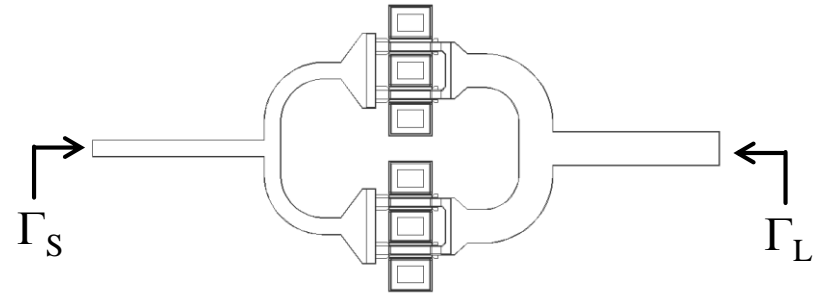
- 3rd Stage FETs
- 2nd Stage FETs
- 1st Stage FET's



The Devil is in the Power Combining

- Symmetric 2-way combiner – Power tuned Γ_S & Γ_L

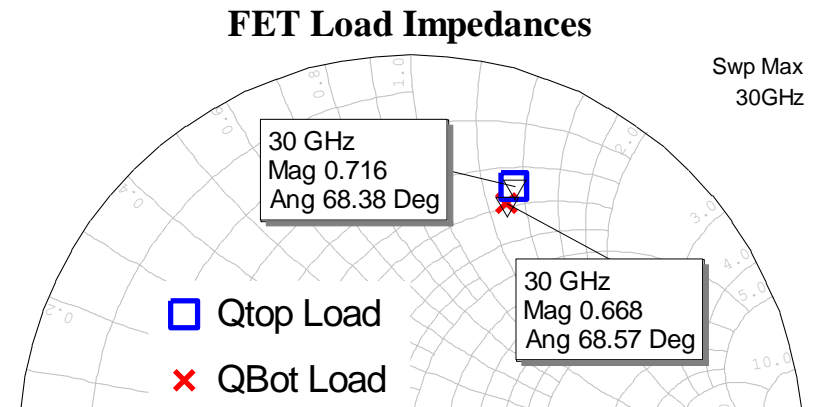
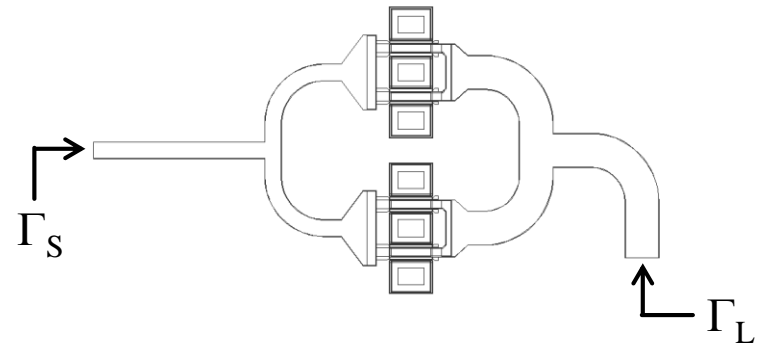
- EM Simulated Combiners
- 4x50 μm 0.15 μm GaN HEMT
- Pwr Tune Γ_L and Γ_S
- Output Power: **31.7dBm**
- Q_{top} Power: **3.82 W/mm**
- Q_{bot} Power: **3.83 W/mm**



The Devil is in the Power Combining

- Curved output line for connection to adjacent pair

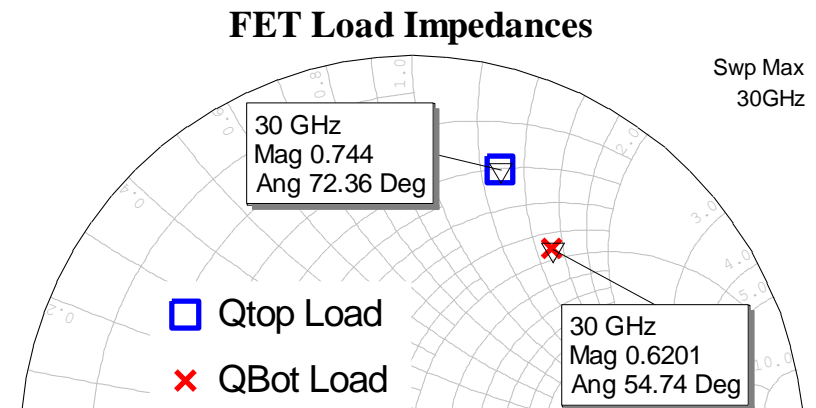
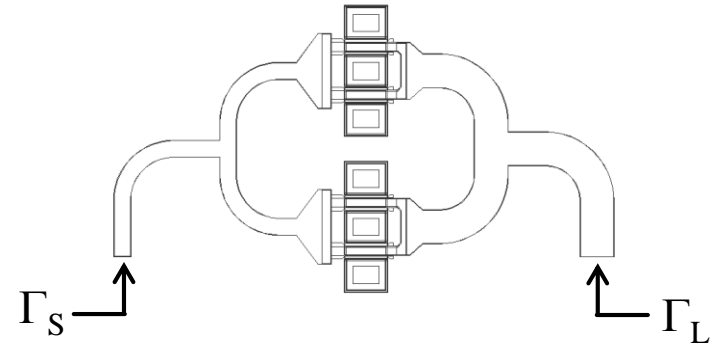
- EM Simulated Combiners
- 4x50 μm 0.15 μm GaN HEMT
- Pwr Tune Γ_L and Γ_S
- Output Power: **31.6dBm**
- Q_{top} Power: **3.74 W/mm**
- Q_{bot} Power: **3.74 W/mm**



The Devil is in the Power Combining

- Curved input and output lines

- EM Simulated Combiners
- 4x50 μm 0.15 μm GaN HEMT
- Pwr Tune Γ_L and Γ_S
- Output Power: **30.2dBm**
- Q_{top} Power: **2.75 W/mm**
- Q_{bot} Power: **2.68 W/mm**



The Devil is in the Power Combining

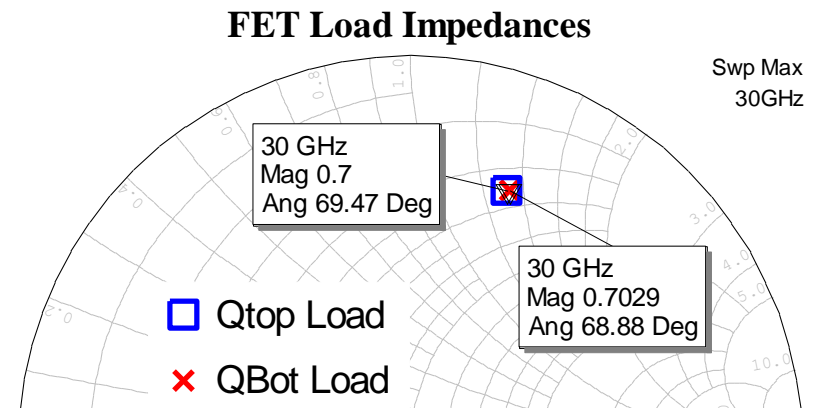
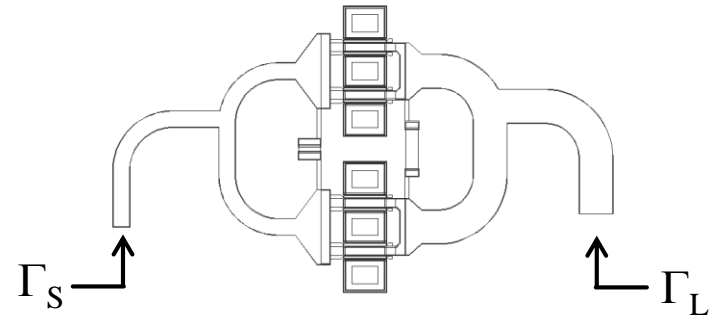
- The output curve causes a minor degradation
- The input curve causes significant degradation
 - Current imbalance due to mode formation from curve
 - The input current imbalance is amplified by the FETs
- Fortunately this effect can be compensated for
 - Addition of odd mode suppression resistors or straps
 - Shifting the location of the tee junction



The Devil is in the Power Combining

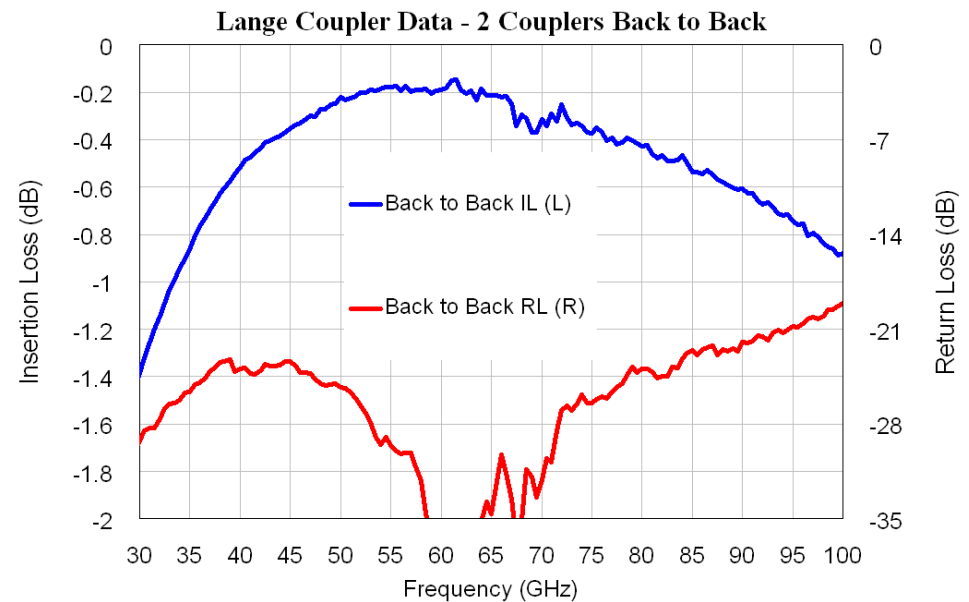
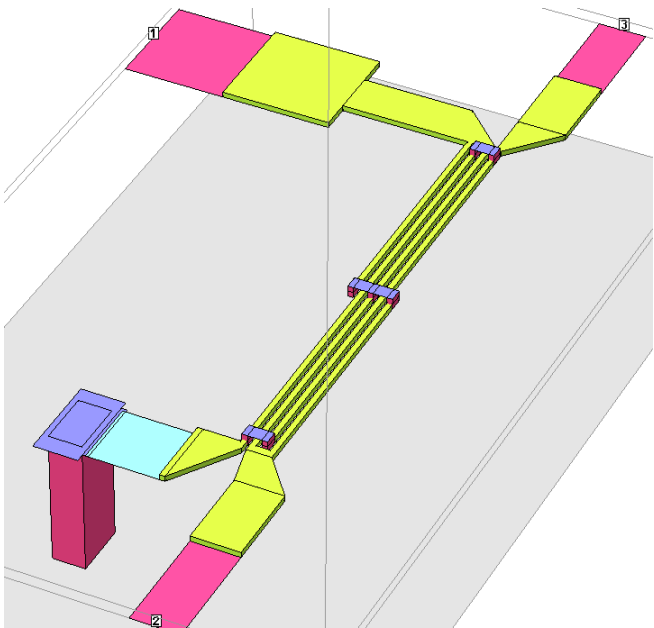
- Compensated curved input and output lines

- Add Odd Mode Resistors
- Offset Tee Junctions
- Pwr Tune Γ_L and Γ_S
- Output Power: **31.7dBm**
- Q_{top} Power: **3.86 W/mm**
- Q_{bot} Power: **3.78 W/mm**



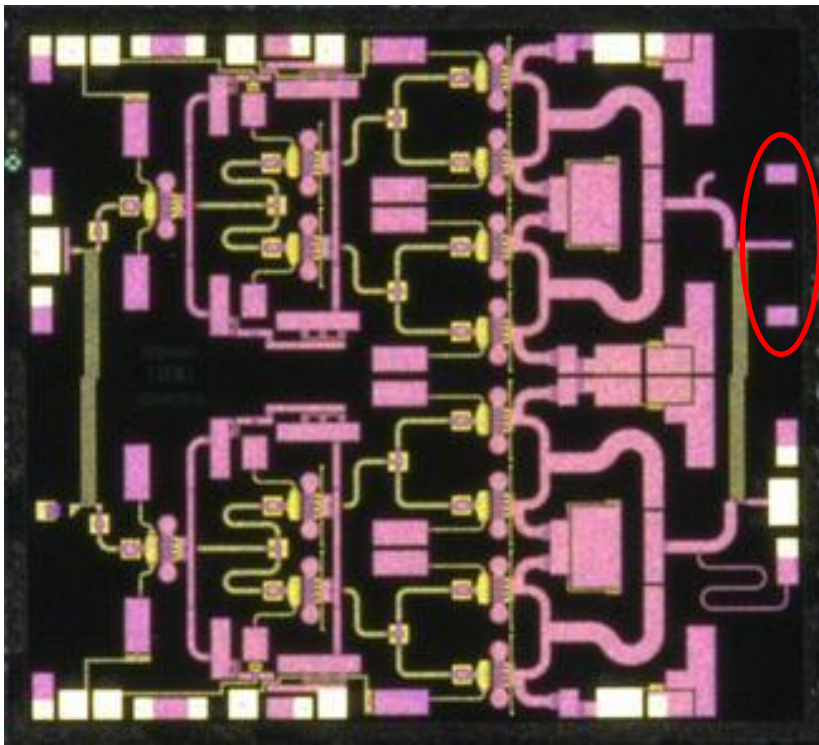
The Devil is in the Power Combining

- Power combining two or more smaller amplifiers is another common approach
- MMIC Lange couplers work very well

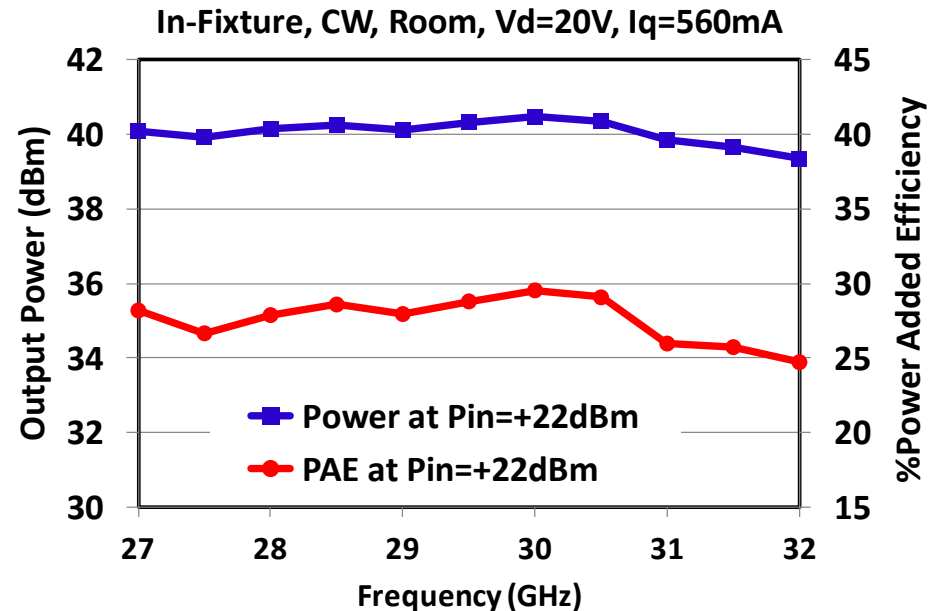


The Devil is in the Power Combining

- Ka-band GaN MMIC example – watch out for the output termination resistor!!! [8]

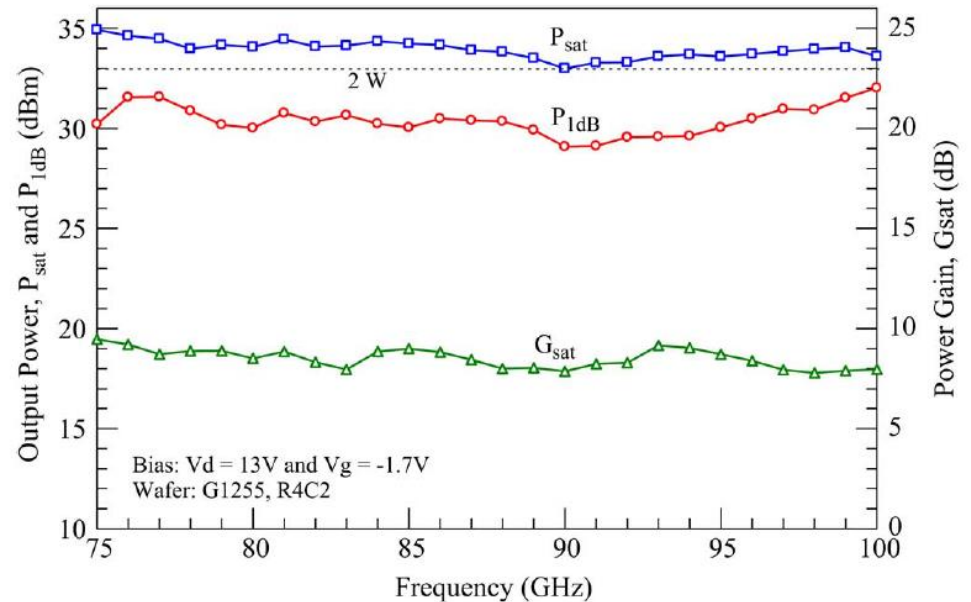
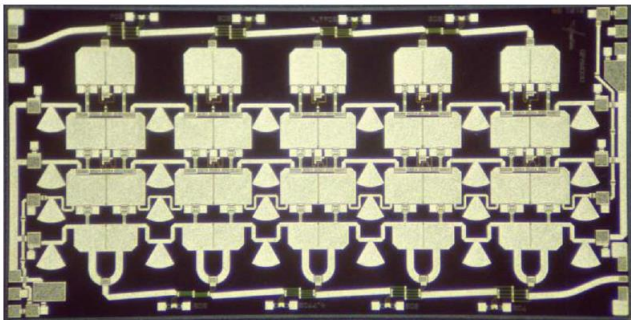
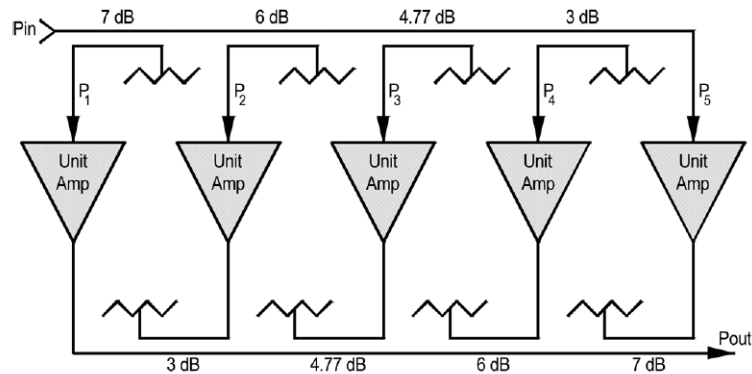


High Power 50 Ω
Termination (2.5W)



The Devil is in the Power Combining

- Recent results using traveling wave like combiners are very encouraging!! [9]



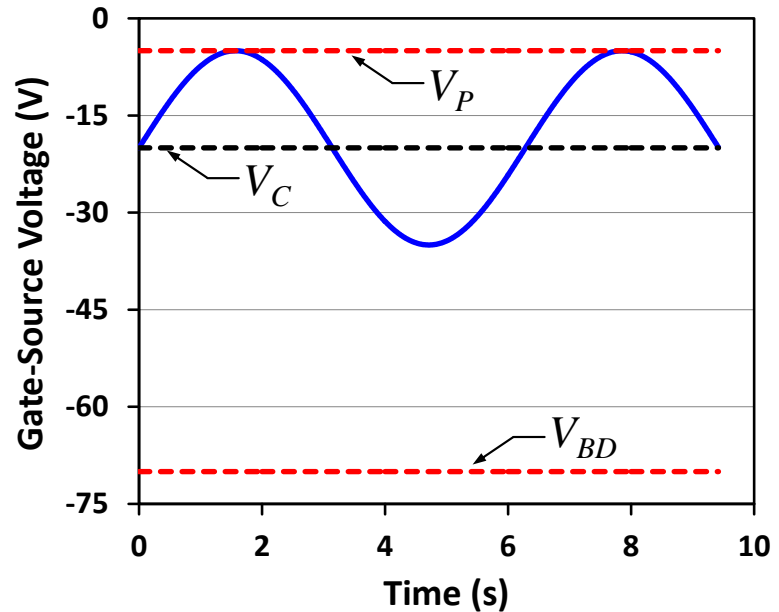
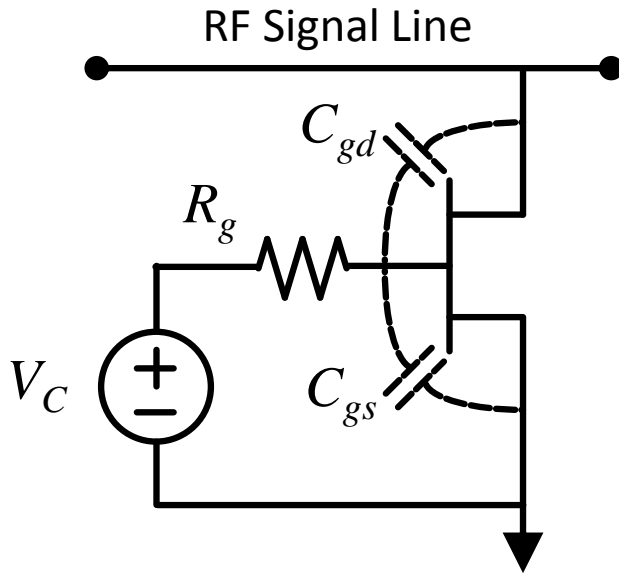
Nice RF Switch But High Control Voltage!

- GaN technology is well suited to RF control circuits
 - High breakdown voltage (V_{BD})
 - High current capability (I_{MAX})
- High control voltage is required, typically -20V to -40V
- Users struggle to build high speed driver circuits
- Lower control voltage range is often requested
- How does the circuit maintain power handling?



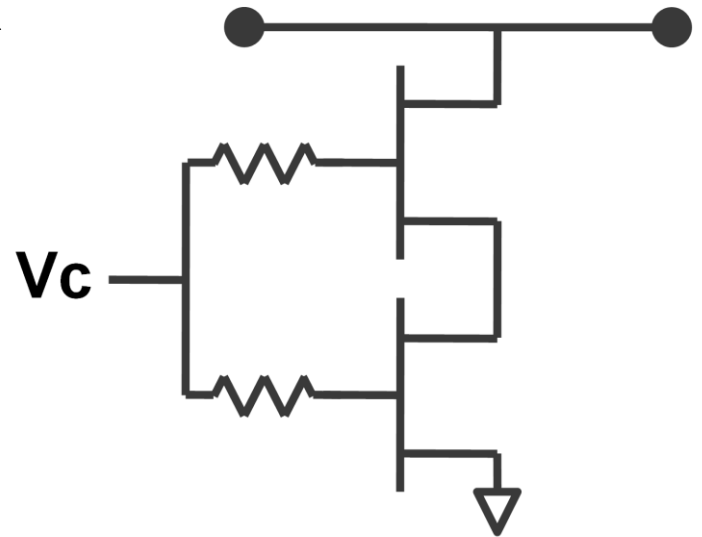
Nice RF Switch But High Control Voltage!

- Typical shunt switch FET circuit ($V_C = -20V$)
- Biased through high value gate resistor
- To increase power handling make V_C more negative



Nice RF Switch But High Control Voltage!

- A common approach is to stack “N” FET cells
 - Up to N^2 power handling increase
 - Up to N^2 increase in FET area
 - More parasitic capacitance
 - Some foundries integrate 3 gate fingers into a single channel \Rightarrow “Triple Gate FET”

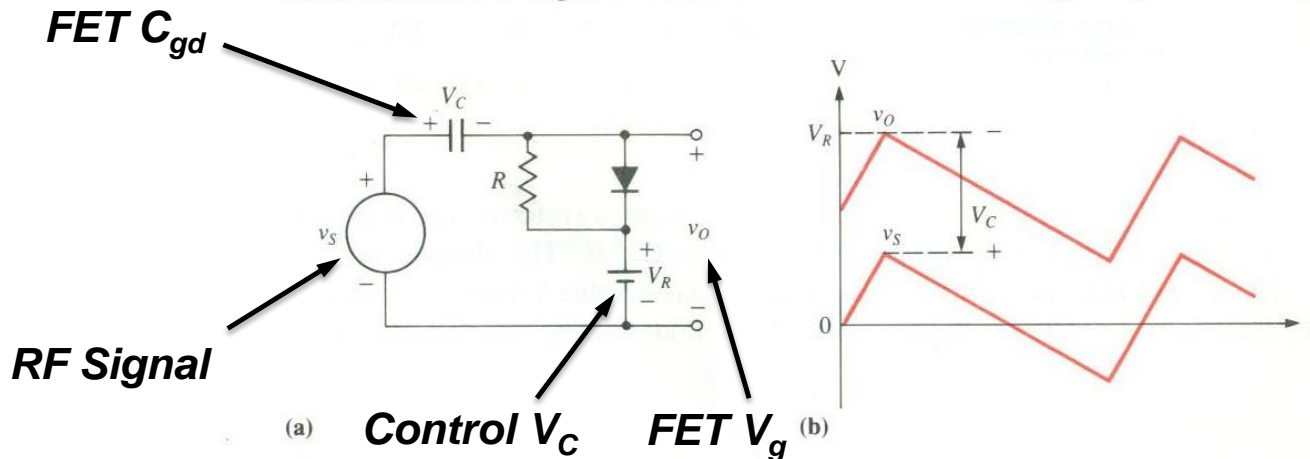


Nice RF Switch But High Control Voltage!

- Consider the diode clamp circuit shown below [10]

3.4 DIODE CLAMPING CIRCUITS

The circuit shown in Fig. 3.17(a) is known as a *clamp* because its function is to “clamp” or fix one edge of a periodic waveform (in this case the positive peak) to some reference voltage. The time constant RC must be long compared to the period

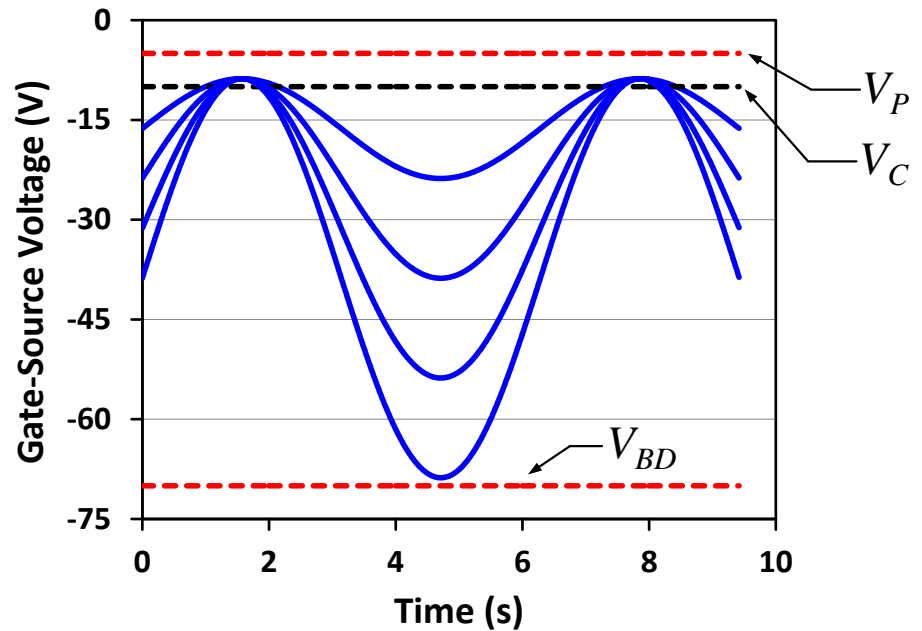
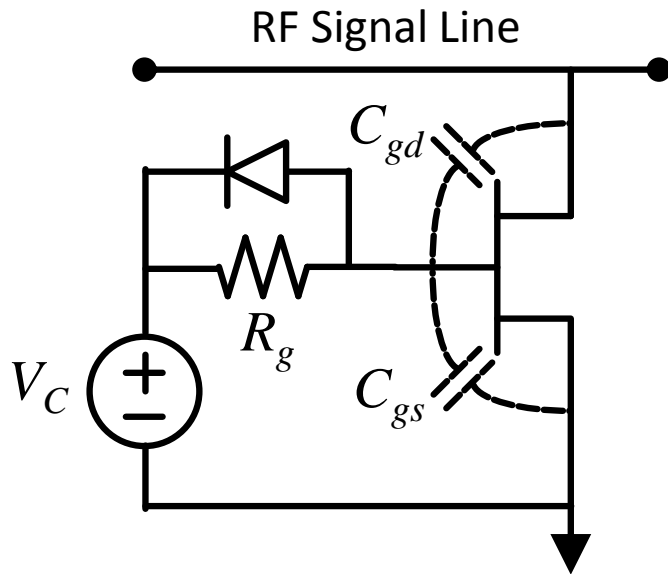


- Note the comment regarding the RC time constant, the clamping action will not occur at low frequency



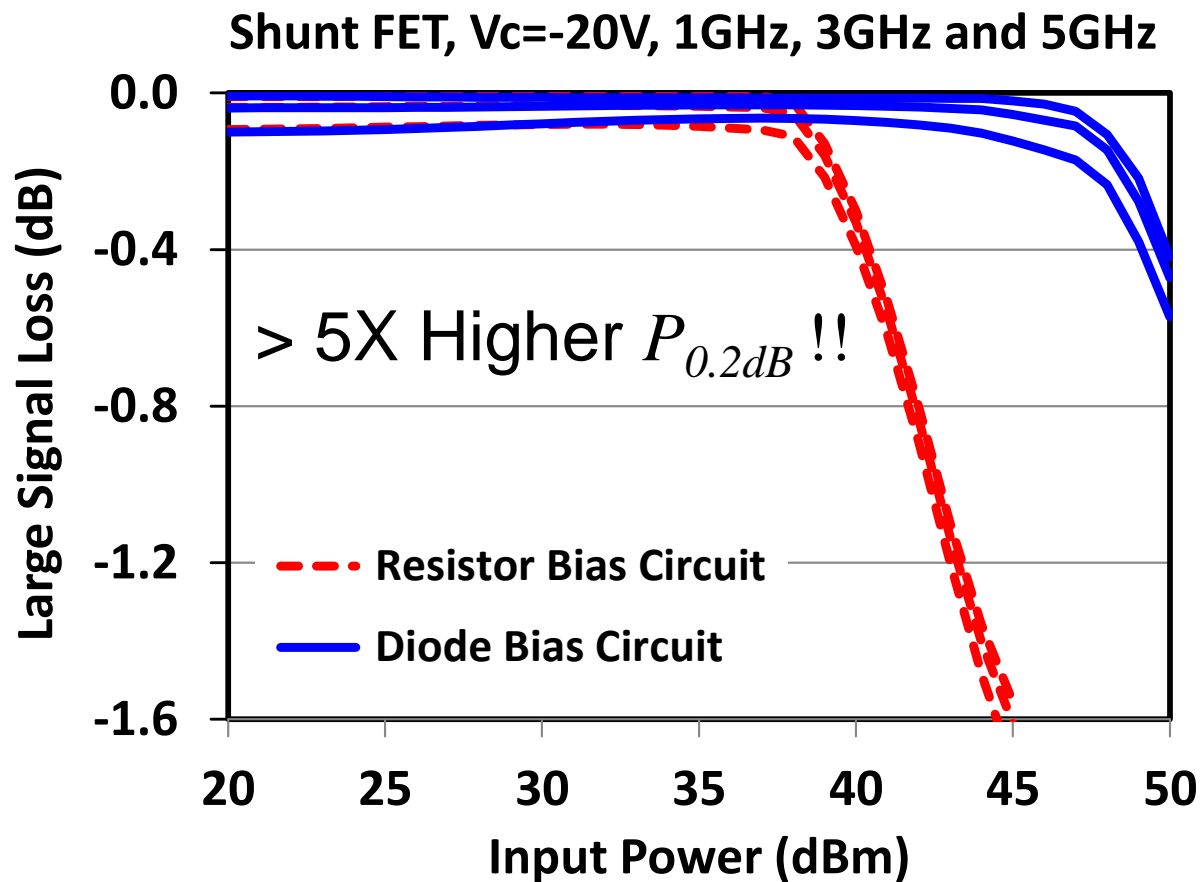
Nice RF Switch But High Control Voltage!

- Add a small gate diode in parallel with R_g
- Schematically equivalent to a diode clamp circuit
- Now control voltage V_C can be made less negative!



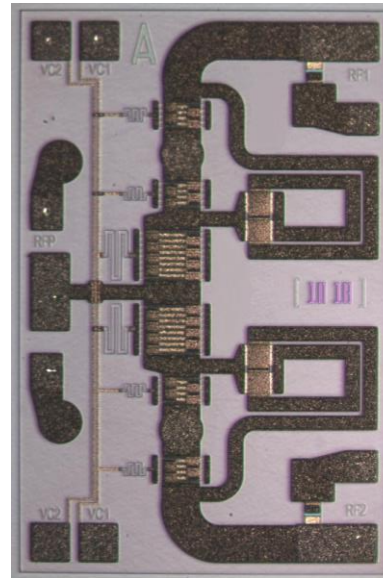
Nice RF Switch But High Control Voltage!

- Simulations with & without the parallel diode

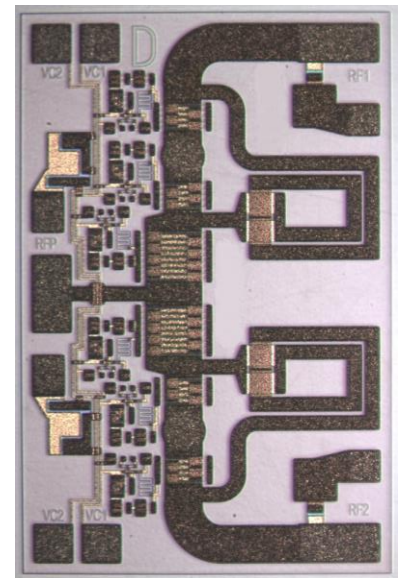


Nice RF Switch But High Control Voltage!

- A 40W GaN switch design was fitted with the diode circuit & processed along side the original
- 0.25 μm GaN Switch FETs
 - Centered Gate
 - Single Field Plate
 - 100 μm SiC
 - $I_{MAX} = 0.95\text{A/mm}$
 - $V_P = -3.1\text{V}$
 - $V_{BD} > 55\text{V}$



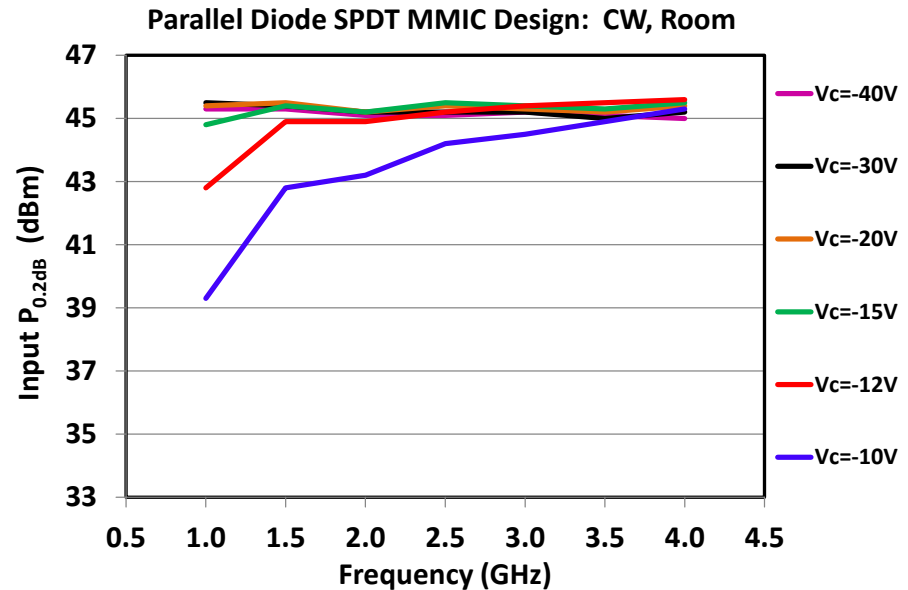
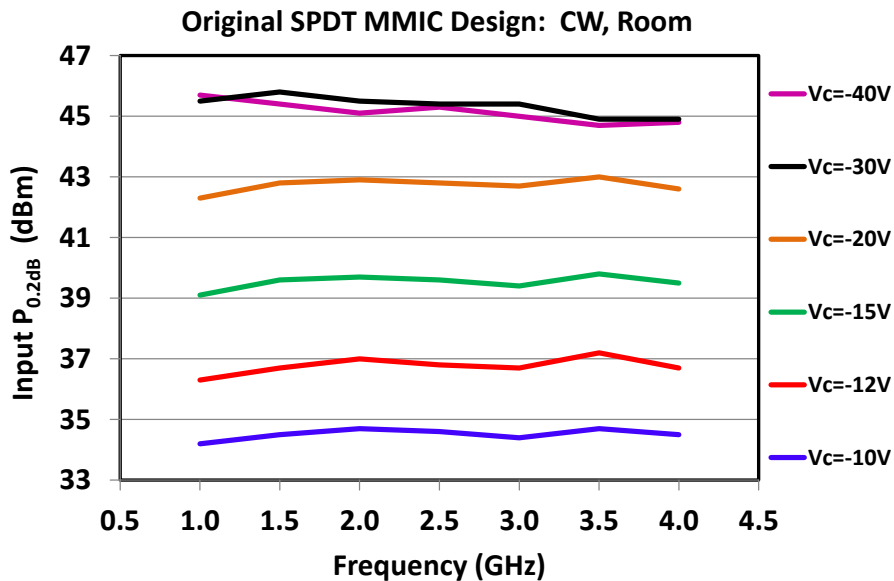
Original SPDT Switch



Retrofitted SPDT Switch

Nice RF Switch But High Control Voltage!

- Measured CW $P_{0.2dB}$ compression point [11,12]
 - Frequency response of clamp is evident
 - 10X increase in $P_{0.2dB}$ above 2.5GHz for -10V V_C



Concluding Remarks

- GaN MMIC technology is a real game changer
- The enabling characteristics do come with issues
- Hopefully this talk has illustrated some of the challenges associated with GaN MMIC design

Thank you for the opportunity to
speak today!



References

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- [2] G. D. Vendelin, A. M. Pavio and U. L. Rohde, Microwave Circuit Design Using Linear and Nonlinear Techniques, John Wiley and Sons, 2005.
- [3] C. Duperrier et al., "New Design Method of Uniform and Nonuniform Distributed Power Amplifiers", IEEE Trans. Microw. Theory Techn., vol. 49, pp. 2494-2500, Dec. 2001.
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- [11] C. F. Campbell, “Method to Reduce Control Voltage for High Power GaN RF Switches”, IEEE MTT-S Int. Microwave Symp. Dig., 2015.
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